## Notice of References Cited

Application/Control No.

10/009,704

Examiner

Yelena G. Gakh, Ph.D.

Applicant(s)/Patent Under
Reexamination
WALKER ET AL.

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## U.S. PATENT DOCUMENTS

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## FOREIGN PATENT DOCUMENTS

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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Harris "Quantitative Chemical Analysis", Chapter 19 "Fundamentals of Spectrophotometry", Freeman & Co, NY, 1999, pages 511-517
	٧	Christian "Analytical Chemistry", John Wiley & Sons, 1990, page 378
	W	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.